March 2013



FQN1N50C

# N-Channel QFET MOSFET

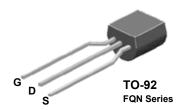
**500 V, 0.38 A, 6** Ω

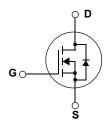
# **Description**

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.



- 0.38 A, 500 V,  $R_{DS(on)}$  = 6  $\Omega$  (Max) @ $V_{GS}$  = 10 V,  $I_D$  = 0.19 A
- Low Gate Charge (Typ. 4.9 nC)
- Low Crss (Typ. 4.1 pF)
- 100% Avalanche Tested





# **Absolute Maximum Ratings**

Symbol		Parameter		FQN1N50C	Unit
V <sub>DSS</sub>	Drain-Source V	oltage		500	V
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 25	5°C)	0.38	А
		- Continuous (T <sub>C</sub> = 10	00°C)	0.24	А
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	3.04	A
V <sub>GSS</sub>	Gate-Source Vo	oltage		± 30	V
E <sub>AS</sub>	Single Pulsed A	valanche Energy	(Note 2)	44.4	mJ
I <sub>AR</sub>	Avalanche Curr	ent	(Note 1)	0.38	A
E <sub>AR</sub>	Repetitive Avala	anche Energy	(Note 1)	0.21	mJ
dv/dt	Peak Diode Re	covery dv/dt	(Note 3)	4.5	V/ns
$P_{D}$	Power Dissipati	on (T <sub>A</sub> = 25°C)		0.89	W
	Power Dissipati	on (T <sub>L</sub> = 25°C)		2.08	W
		- Derate above 25°C		0.017	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and S	Storage Temperature R	ange	-55 to +150	°C
T <sub>L</sub>	Maximum lead	temperature for soldering	ng purposes,	300	°C

### **Thermal Characteristics**

Symbol	Parameter		Тур	Max	Unit
$R_{\theta JL}$	Thermal Resistance, Junction-to-Lead	(Note 6a)		60	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 6b)		140	°C/W

# **Package Marking and Ordering Information**

Device Marking	Device Package		Reel Size	Tape Width	Quantity	
1N50C	FQN1N50C	TO-92	-	-	2000ea	

# **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Characte	ristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	500			V
$\Delta BV_{DSS}/$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.5		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V			50	μА
		V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125°C			250	μА
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Characte	ristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.19 A		4.6	6.0	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 0.19A (Note 4)		0.6		S
Dynamic Cha	aracteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		150	195	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		28	40	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			4.1		pF
Switching Cl	naracteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 250 V, I <sub>D</sub> = 1.0 A,		10	30	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		10	30	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			20	50	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		15	40	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 1.0 A,		4.9	6.4	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		0.66		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)	-	2.9		nC
Drain-Source	e Diode Characteristics and Maximum R	atings				
I <sub>S</sub>	Maximum Continuous Drain-Source Dioc	de Forward Current			0.38	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Fo	orward Current	-		3.04	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 0.38 A	-		1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.0 A,	-	188		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		0.55		μС

#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 80mH,  $I_{AS}$  = 1.0A,  $V_{DD}$  = 50V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C
- 3.  $I_{SD} \leq 0.38 A$ , di/dt  $\leq 200 A/\mu s$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J$  = 25°C
- 4. Pulse Test : Pulse width  $\leq 300 \mu s,$  Duty cycle  $\leq 2\%$
- 5. Essentially independent of operating temperature
- 6. a) Reference point of the R<sub>B,IL</sub> is the drain lead b) When mounted on 3"x4.5" FR-4 PCB without any pad copper in a still air environment

 $(R_{\theta JA})$  is the sum of the junction-to-case and case-to-ambient thermal resistance.  $R_{\theta CA}$  is determined by the user's board design)

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

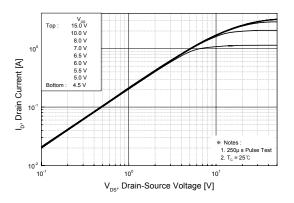


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

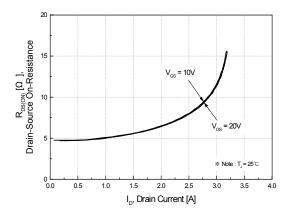


Figure 5. Capacitance Characteristics

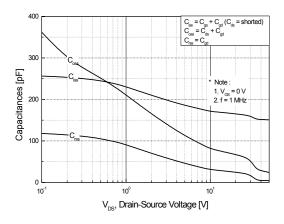


Figure 2. Transfer Characteristics

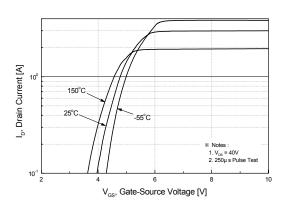


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

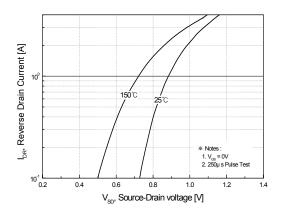
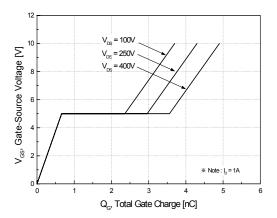


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

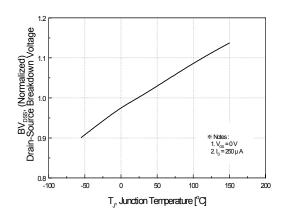


Figure 8. On-Resistance Variation vs. Temperature

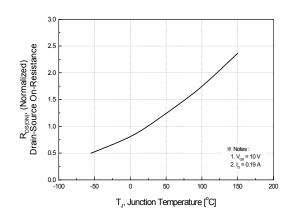


Figure 9. Maximum Safe Operating Area

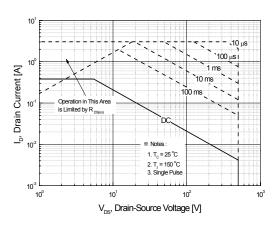


Figure 10. Maximum Drain Current vs. Case Temperature

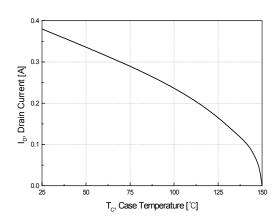
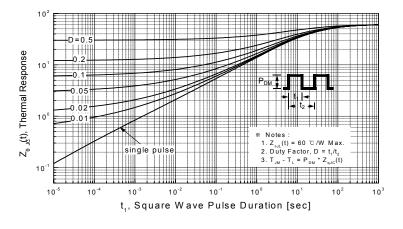
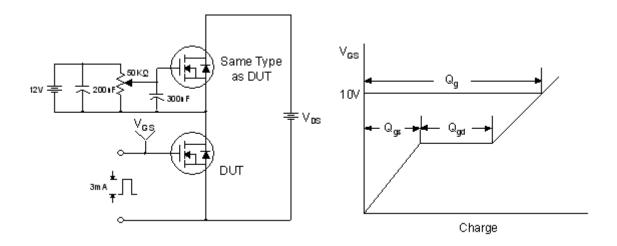


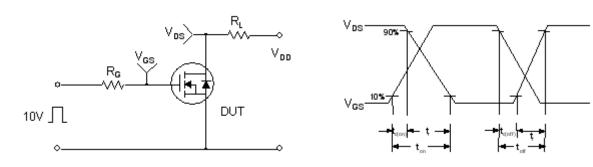
Figure 11. Transient Thermal Response Curve



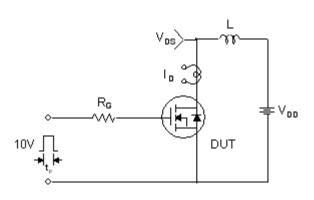
### **Gate Charge Test Circuit & Waveform**

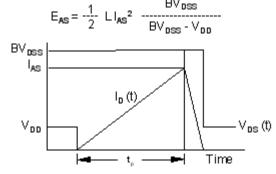


### **Resistive Switching Test Circuit & Waveforms**

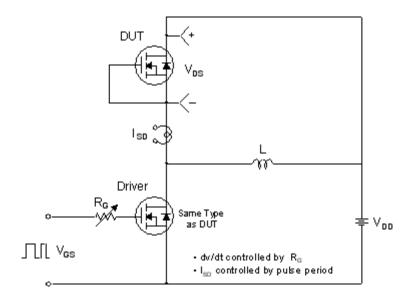


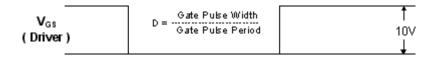
### **Unclamped Inductive Switching Test Circuit & Waveforms**

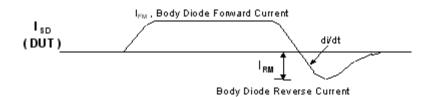


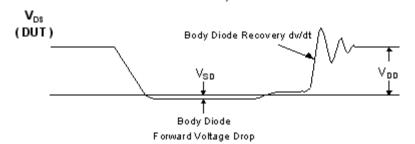


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



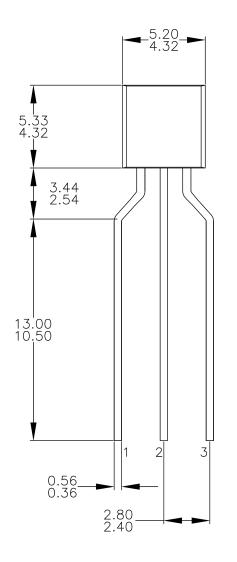


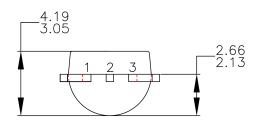


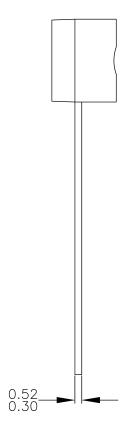


## **Mechanical Dimensions**

**TO-92** 







NOTES: UNLESS OTHERWISE SPECIFIED

- DRAWING WITH REFERENCE TO JEDEC TO-92 RECOMMENDATIONS.
  ALL DIMENSIONS ARE IN MILLIMETERS.
  DRAWING CONFORMS TO ASME Y14.5M-1994.
  TO-92 (92,94,96,97,98) PIN CONFIGURATION:

Z	14		92			94			96			97			98		
٥		Р	F	М	Р	F	М	В	F	М	Р	F	М	Р	F	М	
1		Ε	S	S	Ε	S	S	В	D	G	С	G	D	С	G	D	
2	- 2	В	D	G	C	G	D	Ε	S	S	В	D	G	Ε	S	S	
3	5	С	G	D	В	D	G	С	G	D	Ε	S	S	В	D	G	

#### LEGEND:

P - BIPOLAR F - JFET M - DMOS E - EMITTER B - BASE C - COLLECTOR D - DRAIN S - SOURCE G - GATE

- E) FOR PACKAGE 92, 94, 96, 97 AND 98:
  PIN CONFIGURATION DRAIN "D" AND SOURCE "S"
  ARE INTERCHANGEAGLE AT JFET "F" OPTION.
  F) DRAWING FILENAME: MKT—ZAO3FREV2.

Dimensions in Millimeters





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